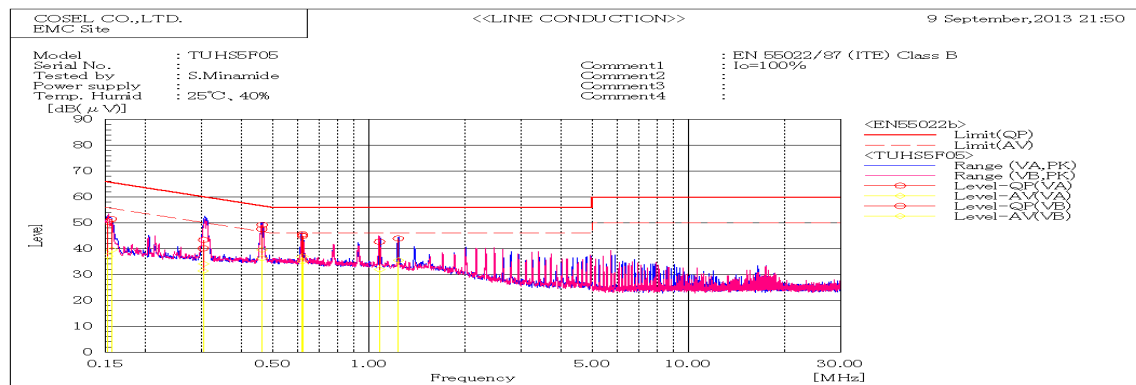
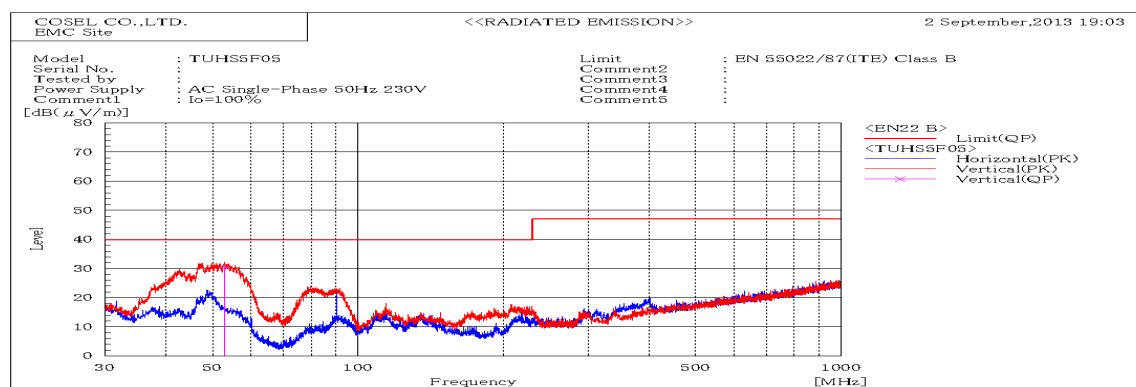


DATA SHEET

DATA SHEET		Date	16-Dec-13
Model	TUHS5F05	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	S.Minamide



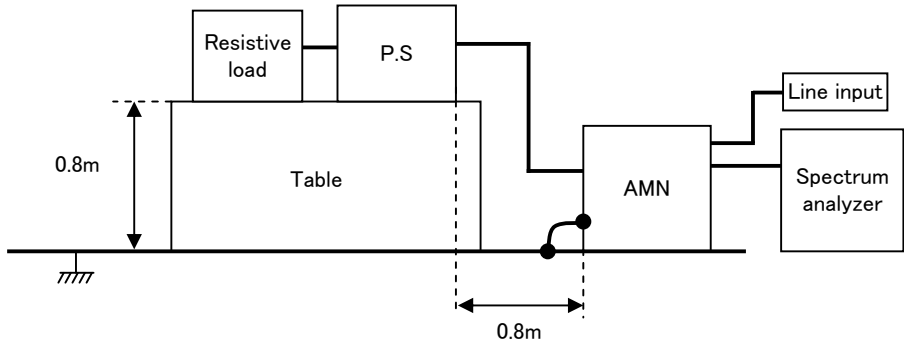
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15667		VA	31.3	19.3	20.2	51.5	39.5	65.6	55.6	14.1	16.1	Pass	
0.15252		VB	30.3	17.0	20.2	50.5	37.2	65.9	55.9	15.4	18.7	Pass	
0.30438		VA	23.3	13.9	20.1	43.4	34.0	60.1	50.1	16.7	16.1	Pass	
0.30328		VB	20.0	11.3	20.1	40.1	31.4	60.2	50.2	20.1	18.8	Pass	
0.46432		VA	29.1	19.5	20.1	49.2	39.6	56.6	46.6	7.4	7.0	Pass	
0.463		VB	27.5	16.2	20.1	47.6	36.3	56.6	46.6	9.0	10.3	Pass	
0.6197		VA	25.5	16.8	20.1	45.6	36.9	56.0	46.0	10.4	9.1	Pass	
0.6202		VB	24.8	15.0	20.1	44.9	35.1	56.0	46.0	11.1	10.9	Pass	
1.08051		VB	22.5	11.7	20.2	42.7	31.9	56.0	46.0	13.3	14.1	Pass	
1.23729		VA	23.7	15.3	20.2	43.9	35.5	56.0	46.0	12.1	10.5	Pass	



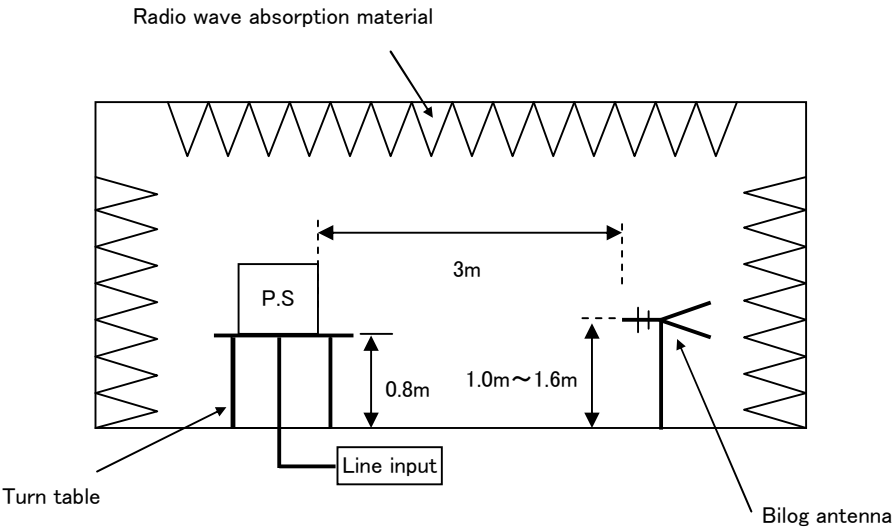
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
53.078	V	Stable	54.2	-23.7		30.5		40	9.5	Pass	103	98	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	S.Minamide

1. Line conduction



2. Radiated emission



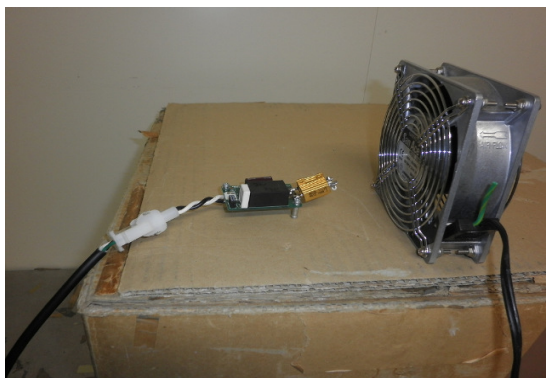
Conditions

Test: EMI

Model Name: TUHS5F□□

○ Photographs of Test Set-Up

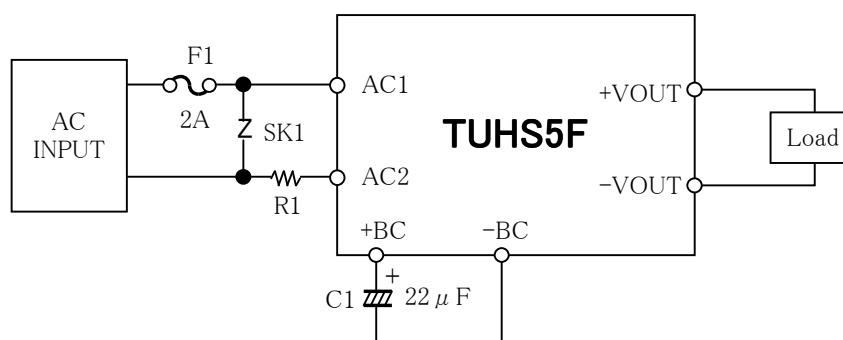
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 1K100JA (TAMURA THERMAL DEVICE)

SK1: TND10V-511K (NIPPON CHEMI-CON)

2A

10Ω

Fig.1 Testing circuitry